

- ★ Green Device Available
- ★ Super Low Gate Charge
- ★ Excellent CdV/dt effect decline
- ★ Advanced high cell density Trench technology
- ★ 100% EAS Guaranteed

### Product Summary

**RoHS**

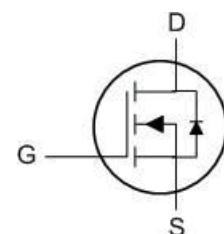
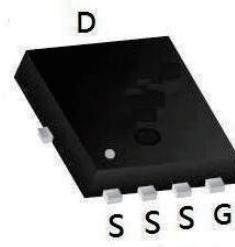
BVDSS	RDSON	ID
30V	7mΩ	50A

### Description

The 50N03D is the high cell density trenched N-ch MOSFETs, which provide excellent RDSON and gate charge for most of the synchronous buck converter applications.

The 50N03D meet the RoHS and Green Product, requirement 100% EAS guaranteed with full function reliability approved.

### PDFN3\*3 Pin Configuration



### Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D @ T_c=25^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	50	A
$I_D @ T_c=100^\circ C$	Continuous Drain Current, $V_{GS} @ 10V^1$	30	A
$I_{DM}$	Pulsed Drain Current <sup>2</sup>	120	A
$E_{AS}$	Single Pulse Avalanche Energy <sup>3</sup>	39	mJ
$I_{AS}$	Avalanche Current	50	A
$P_D @ T_c=25^\circ C$	Total Power Dissipation <sup>4</sup>	18	W
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

### Thermal Data

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction-ambient <sup>1</sup>	---	75	°C/W
$R_{\theta JC}$	Thermal Resistance Junction-Case <sup>1</sup>	---	4.32	°C/W

Electrical Characteristics ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_{\text{D}}=250\mu\text{A}$	30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	$\text{BV}_{\text{DSS}}$ Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_{\text{D}}=1\text{mA}$	-	0.027	-	$\text{V}/^\circ\text{C}$
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_{\text{D}}=12\text{A}$	-	7	8.5	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$ , $I_{\text{D}}=10\text{A}$	-	10	14	
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage		1	-	2.5	V
$\Delta V_{\text{GS}(\text{th})}$	$V_{\text{GS}(\text{th})}$ Temperature Coefficient	$V_{\text{GS}}=V_{\text{DS}}$ , $I_{\text{D}}=250\mu\text{A}$	-	-5.8	-	$\text{mV}/^\circ\text{C}$
$I_{\text{DSS}}$	Drain-Source Leakage Current	$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=25^\circ\text{C}$	-	-	1	$\text{uA}$
		$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $T_J=55^\circ\text{C}$	-	-	5	
$I_{\text{GSS}}$	Gate-Source Leakage Current	$V_{\text{GS}}=\pm 20\text{V}$ , $V_{\text{DS}}=0\text{V}$	-	-	$\pm 100$	nA
$R_g$	Gate Resistance	$V_{\text{DS}}=0\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	-	1.7	-	$\Omega$
$Q_g$	Total Gate Charge (4.5V)		-	12.8	-	
$Q_{\text{gs}}$	Gate-Source Charge	$V_{\text{DS}}=20\text{V}$ , $V_{\text{GS}}=4.5\text{V}$ , $I_{\text{D}}=12\text{A}$	-	3.3	-	$\text{nC}$
$Q_{\text{gd}}$	Gate-Drain Charge		-	6.5	-	
$T_{\text{d}(\text{on})}$	Turn-On Delay Time		-	4.5	-	
$T_r$	Rise Time	$V_{\text{DD}}=12\text{V}$ , $V_{\text{GS}}=10\text{V}$ , $R_G=3.3\Omega$ $I_{\text{D}}=5\text{A}$	-	10.8	-	ns
$T_{\text{d}(\text{off})}$	Turn-Off Delay Time		-	25.5	-	
$T_f$	Fall Time		-	9.6	-	
$C_{\text{iss}}$	Input Capacitance		-	1200	-	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=15\text{V}$ , $V_{\text{GS}}=0\text{V}$ , $f=1\text{MHz}$	-	163	-	
$C_{\text{rss}}$	Reverse Transfer Capacitance		-	131	-	

## Diode Characteristics

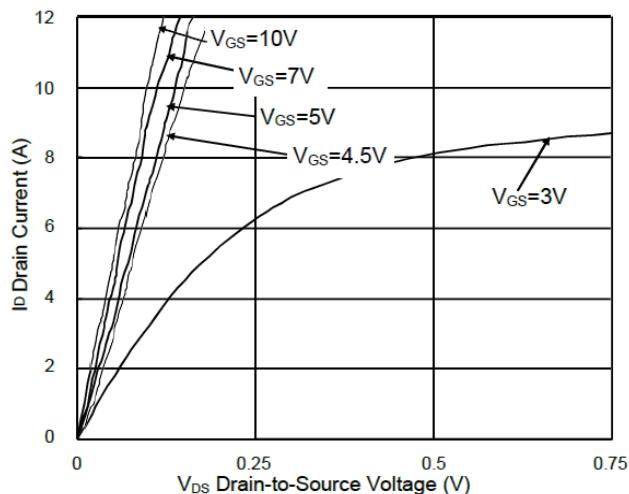
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current <sup>1,6</sup>	$V_G=V_D=0\text{V}$ , Force Current	-	-	50	A
$I_{\text{SM}}$	Pulsed Source Current <sup>2,6</sup>		-	-	120	A
$V_{\text{SD}}$	Diode Forward Voltage <sup>2</sup>	$V_{\text{GS}}=0\text{V}$ , $I_s=1\text{A}$ , $T_J=25^\circ\text{C}$	-	-	1.2	V

## Note :

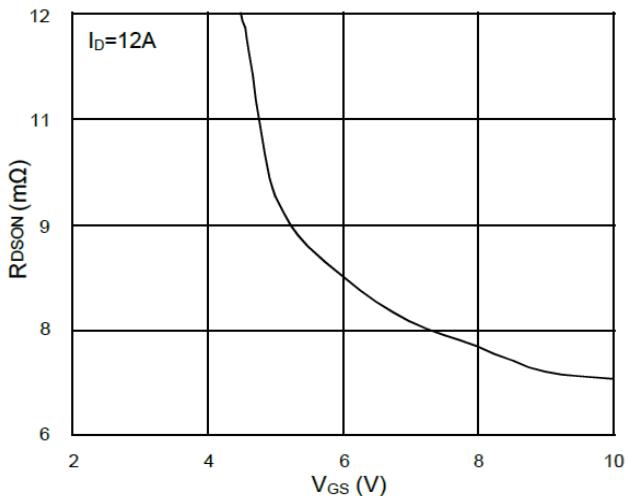
- 1.The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width  $\leq 300\mu\text{s}$  , duty cycle  $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is  $V_{\text{DD}}=25\text{V}$ , $V_{\text{GS}}=10\text{V}$ , $L=0.1\text{mH}$ , $I_{\text{AS}}=34\text{A}$
- 4.The power dissipation is limited by  $150^\circ\text{C}$  junction temperature
- 5.The data is theoretically the same as  $I_D$  and  $I_{\text{DM}}$  , in real applications , should be limited by total power dissipation.

### Typical Performance Characteristics

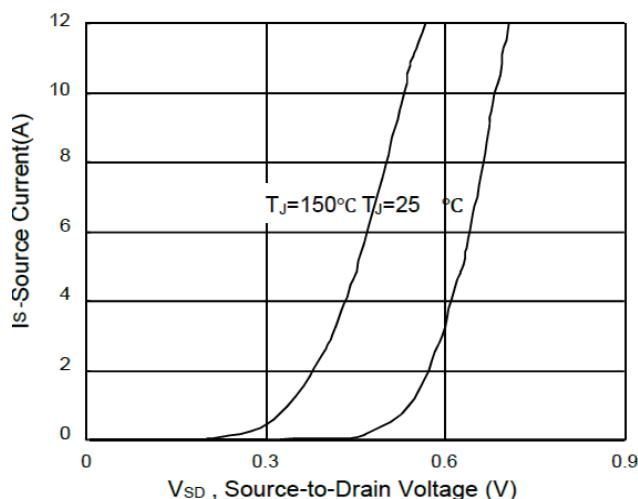
**Figure 1: Output Characteristics**



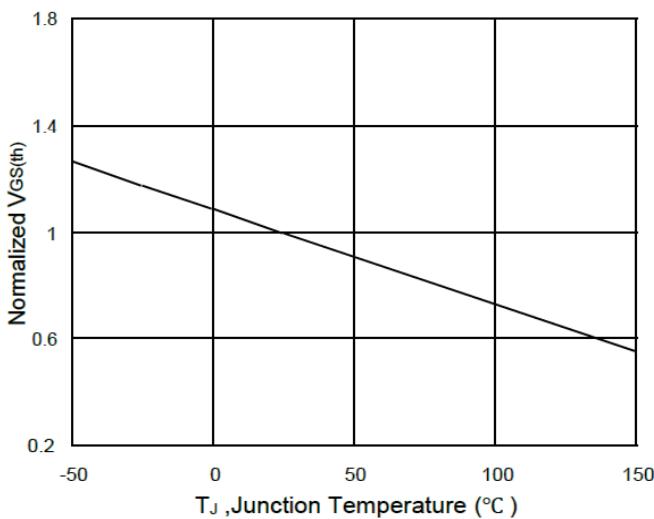
**Figure 2: On-Resistance vs. G-S Voltage**



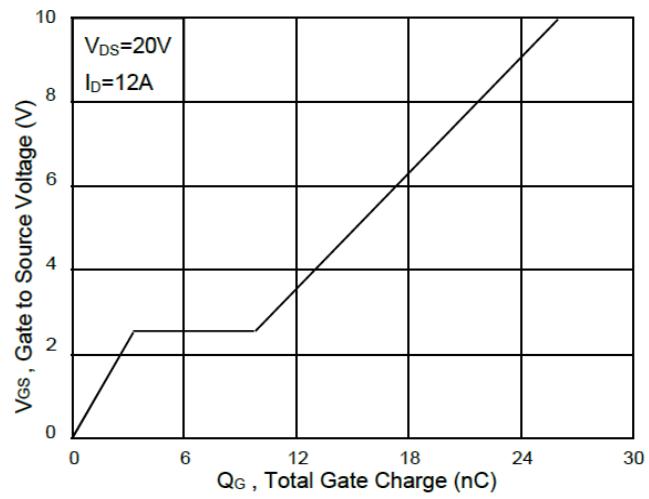
**Figure 3: Forward Characteristics of Reverse Bias**



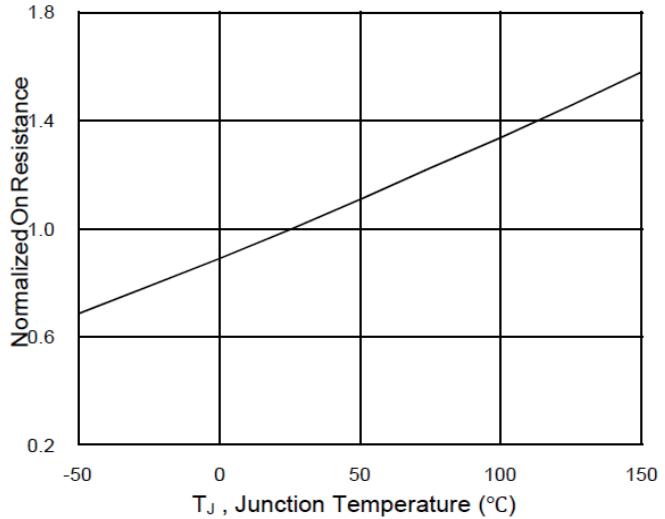
**Figure 5: Normalized VGS(th) vs. TJ**



**Figure 4: Gate-Charge Characteristics**



**Figure 6: Normalized RDS(on) vs. TJ**



## Typical Performance Characteristics

Figure 7: Capacitances. Junction Temperature

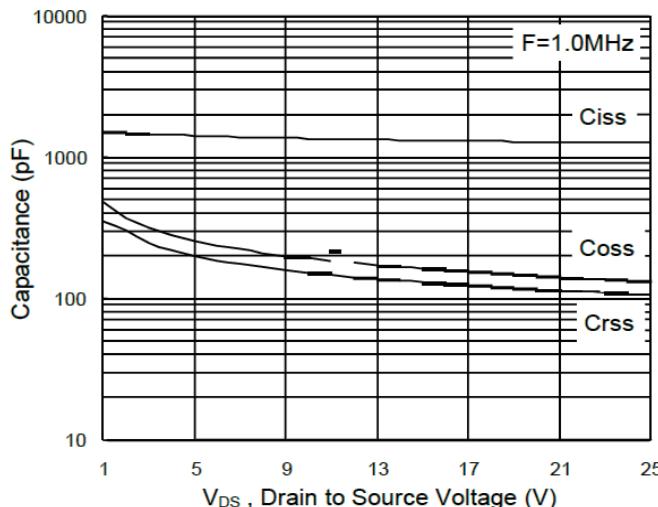


Figure 8: Safe Operating Area

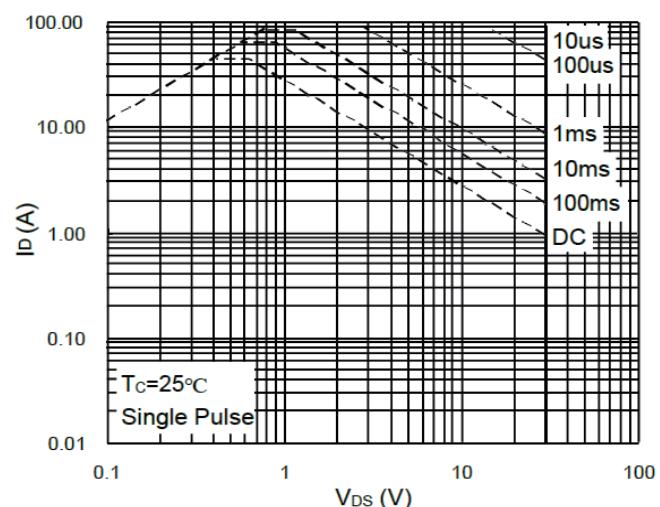


Figure 9: Normalized Maximum Transient Thermal Resistance

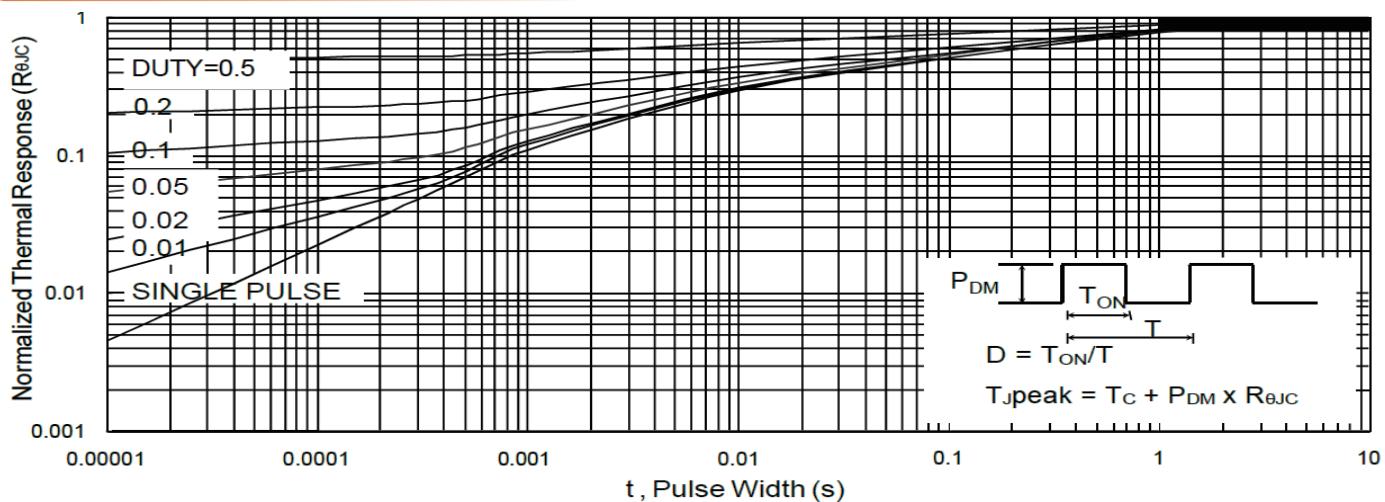


Figure 10: Switching Time Waveform

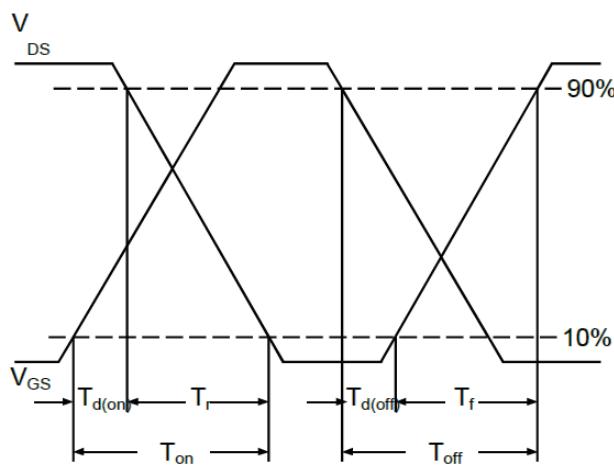
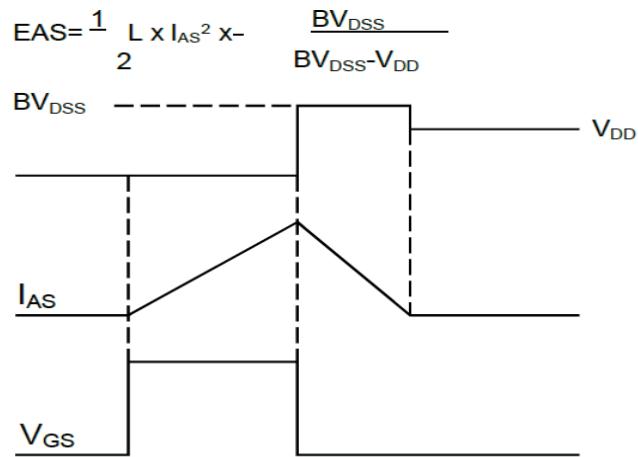
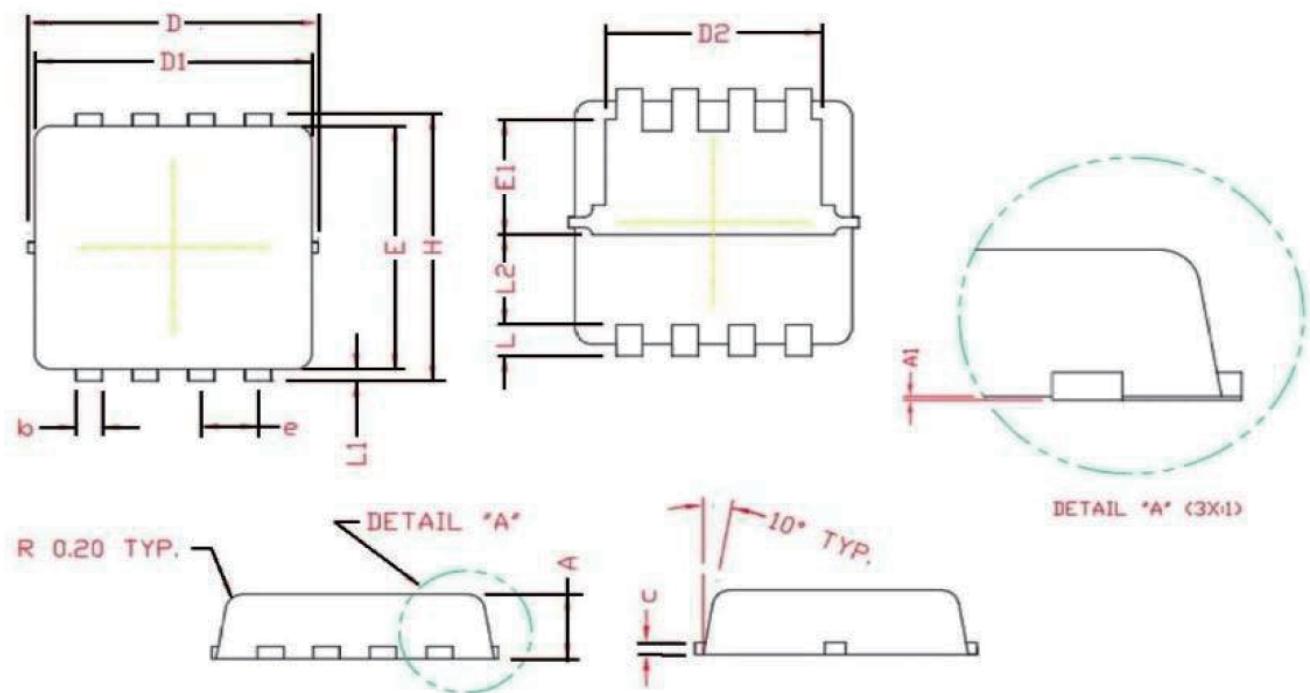


Figure 11: Unclamped Inductive Switching





## PDFN3\*3-8L Package Information



Symbol	MILLIMETER		
	MIN	MON	MAX
A	0.70	0.80	0.90
A1	0.00	0.03	0.05
b	0.24	0.30	0.35
c	0.10	0.15	0.20
D	3.25	3.32	3.40
D1	3.05	3.15	3.25
D2	2.40	2.50	2.60
E	3.00	3.10	3.20
E1	1.35	1.45	1.55
e	0.65BSC.		
H	3.20	3.30	3.40
L	0.30	0.40	0.50
L1	0.10	0.15	0.20
L2	1.13REF.		